Applicant(s)/Patent Under Application/Control No. Reexamination 10/767,077 TANAKA ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 2621 Mitiku Debelie **U.S. PATENT DOCUMENTS Document Number** Date Classification Name Country Code-Number-Kind Code MM-YYYY US-Α US-В US-С US-D US-Ε F US-US-G US-Н US-1 US-J US-Κ US-L US-М **FOREIGN PATENT DOCUMENTS Document Number** Date Classification Country Name Country Code-Number-Kind Code MM-YYYY Ν 0 Р Q R s Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U

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